

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	3196668	@ad<"20010322"	USPAT	OR	ON	2005/03/18 16:03
L2	577873	semiconductor or IC or LSI or VLSI or ASIC or chip or wafer	USPAT	OR	ON	2005/03/18 16:03
L3	3917	metrological or metrology	USPAT	OR	ON	2005/03/18 16:03
L4	286	field-to-field or (field adj to adj field)	USPAT	OR	ON	2005/03/18 16:03
L5	1409232	analys\$ or data or measurement or error	USPAT	OR	ON	2005/03/18 16:03
L6	3910	residual-error or (residual adj error) or (residu\$ adj (error or data or analysis or measurement))	USPAT	OR	ON	2005/03/18 16:03
L7	2	(semiconductor or IC or LSI or VLSI or ASIC or chip or wafer) and (metrological or metrology) and (field-to-field or (field adj to adj field)) and (analys\$ or data or measurement or error)	USPAT	OR	ON	2005/03/18 16:03
L8	2	(semiconductor or IC or LSI or VLSI or ASIC or chip or wafer) and ((field-to-field or (field adj to adj field)) same (analys\$ or data or measurement or error)) and (residual-error or (residual adj error) or (residu\$ adj (error or data or analysis or measurement)))	USPAT	OR	ON	2005/03/18 16:03
L9	2	(semiconductor or IC or LSI or VLSI or ASIC or chip or wafer) and (field-to-field or (field adj to adj field)) and (analys\$ or data or measurement or error) and (residual-error or (residual adj error) or (residu\$ adj (error or data or analysis or measurement)))	USPAT	OR	ON	2005/03/18 16:03
L10	495	703/6.ccls.	USPAT	OR	ON	2005/03/18 16:03
L11	859	430/22.ccls.	USPAT	OR	ON	2005/03/18 16:03
L12	191	382/147.ccls.	USPAT	OR	ON	2005/03/18 16:03
L13	1544	703/6.ccls. or 430/22.ccls. or 382/147.ccls.	USPAT	OR	ON	2005/03/18 16:03
L14	1227	(703/6.ccls. or 430/22.ccls. or 382/147.ccls.) and @ad<"20010322"	USPAT	OR	ON	2005/03/18 16:03
L15	699	((703/6.ccls. or 430/22.ccls. or 382/147.ccls.) and @ad<"20010322") and (semiconductor or IC or LSI or VLSI or ASIC or chip or wafer)	USPAT	OR	ON	2005/03/18 16:03

L16	2	((703/6.ccls. or 430/22.ccls. or 382/147.ccls.) and @ad<"20010322") and (semiconductor or IC or LSI or VLSI or ASIC or chip or wafer) and (field-to-field or (field adj to adj field)))	USPAT	OR	ON	2005/03/18 16:03
L17	3196668	@ad<"20010322"	USPAT	OR	ON	2005/03/18 16:03
L18	577873	semiconductor or IC or LSI or VLSI or ASIC or chip or wafer	USPAT	OR	ON	2005/03/18 16:03
L19	3917	metrological or metrology	USPAT	OR	ON	2005/03/18 16:03
L20	286	field-to-field or (field adj to adj field)	USPAT	OR	ON	2005/03/18 16:03
L21	1409232	analys\$ or data or measurement or error	USPAT	OR	ON	2005/03/18 16:03
L22	3910	residual-error or (residual adj error) or (residu\$ adj (error or data or analysis or measurement))	USPAT	OR	ON	2005/03/18 16:03
L23	2	(semiconductor or IC or LSI or VLSI or ASIC or chip or wafer) and ((field-to-field or (field adj to adj field)) same (analys\$ or data or measurement or error)) and (residual-error or (residual adj error) or (residu\$ adj (error or data or analysis or measurement)))	USPAT	OR	ON	2005/03/18 16:03
L24	495	703/6.ccls.	USPAT	OR	ON	2005/03/18 16:03
L25	859	430/22.ccls.	USPAT	OR	ON	2005/03/18 16:03
L26	191	382/147.ccls.	USPAT	OR	ON	2005/03/18 16:03
L27	1544	703/6.ccls. or 430/22.ccls. or 382/147.ccls.	USPAT	OR	ON	2005/03/18 16:03
L28	1227	(703/6.ccls. or 430/22.ccls. or 382/147.ccls.) and @ad<"20010322"	USPAT	OR	ON	2005/03/18 16:03
L29	699	((703/6.ccls. or 430/22.ccls. or 382/147.ccls.) and @ad<"20010322") and (semiconductor or IC or LSI or VLSI or ASIC or chip or wafer)	USPAT	OR	ON	2005/03/18 16:03
L30	2	(semiconductor or IC or LSI or VLSI or ASIC or chip or wafer) and (metrological or metrology) and (field-to-field or (field adj to adj field)) and (analys\$ or data or measurement or error)	USPAT	OR	ON	2005/03/18 16:03
L31	2	(semiconductor or IC or LSI or VLSI or ASIC or chip or wafer) and (field-to-field or (field adj to adj field)) and (analys\$ or data or measurement or error) and (residual-error or (residual adj error) or (residu\$ adj (error or data or analysis or measurement)))	USPAT	OR	ON	2005/03/18 16:03

L32	2	((703/6.ccls. or 430/22.ccls. or 382/147.ccls.) and @ad<"20010322") and (semiconductor or IC or LSI or VLSI or ASIC or chip or wafer)) and (field-to-field or (field adj to adj field))	USPAT	OR	ON	2005/03/18 16:03
L33	97	wafer-mean or (wafer adj mean)	US-PGPUB; USPAT	OR	OFF	2005/03/18 16:03
L34	0	L33 near2 error	US-PGPUB; USPAT	OR	ON	2005/03/18 16:03
L35	1	L33 and L22	US-PGPUB; USPAT	OR	ON	2005/03/18 16:03